



# CERTIFICATE



This is to certify that

## **MPI CORPORATION**

No. 129 & 155, Chung-Ho Street, Chu-Pei City Hsinchu County 302 Taiwan, R.O.C.

with the organizational units/sites as listed in the annex

has implemented and maintains an Occupational Health and Safety Management System.

Scope:

The occupational health and safety activities and supporting processes associated with the design and manufacture of probe cards and semiconductor test equipment and the design and manufacture of Thermal equipment and the design and manufacture of engineering probe systems and RF probes.

Through an audit, documented in a report, it was verified that the management system fulfills the requirements of the following standard:

## ISO 45001 : 2018

Certificate registration no.	20001936 OHS18
Date of certification	2025-06-16
Valid until	2028-08-31

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DQS Inc.

David Tellez Managing Director

Accredited Body: DQS Inc., 1500 McConnor Parkway, Suite 400, Schaumburg, IL 60173 USA Administrative Office: DQS Taiwan Inc., 8F, 23, Yuan Huan West Road, Feng Yuan Dist., Taichung City, Taiwan 420 **The validity of the certification can only be verified by the QR-code**.

DQS IS A MEMBER OF









### Annex to certificate Registration no.: 20001936 OHS18

## **MPI CORPORATION**

No. 129 & 155, Chung-Ho Street, Chu-Pei City Hsinchu County 302 Taiwan, R.O.C.

#### Location

20001936 MPI CORPORATION No. 155, Chung-Ho Street, Chu-Pei City Hsinchu County 302 Taiwan, R.O.C. Scope

The occupational health and safety activities and supporting processes associated with the design and manufacture of probe cards and the design and manufacture of Thermal equipment and the design and manufacture of engineering probe systems and RF probes.

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No. 129, Chung-Ho Street, Chu-Pei City Hsinchu County 302 Taiwan, R.O.C. The occupational health and safety activities and supporting processes associated with the design and manufacture of semiconductor test equipment.